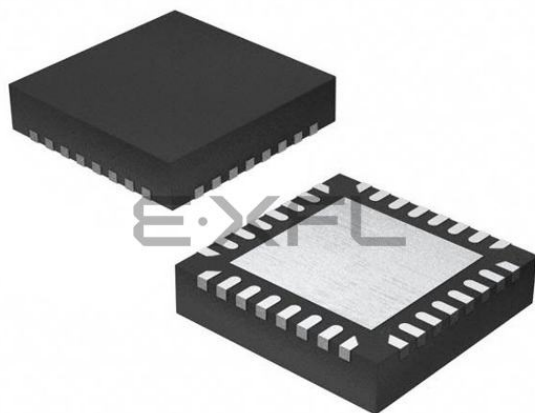




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	32
Number of Logic Elements/Cells	256
Total RAM Bits	-
Number of I/O	21
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-QFN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmx02-256ze-3sg32c

The EBR memory supports three forms of write behavior for single or dual port operation:

1. **Normal** – Data on the output appears only during the read cycle. During a write cycle, the data (at the current address) does not appear on the output. This mode is supported for all data widths.
2. **Write Through** – A copy of the input data appears at the output of the same port. This mode is supported for all data widths.
3. **Read-Before-Write** – When new data is being written, the old contents of the address appears at the output.

FIFO Configuration

The FIFO has a write port with data-in, CEW, WE and CLKW signals. There is a separate read port with data-out, RCE, RE and CLKR signals. The FIFO internally generates Almost Full, Full, Almost Empty and Empty Flags. The Full and Almost Full flags are registered with CLKW. The Empty and Almost Empty flags are registered with CLKR. Table 2-7 shows the range of programming values for these flags.

Table 2-7. Programmable FIFO Flag Ranges

Flag Name	Programming Range
Full (FF)	1 to max (up to 2^N-1)
Almost Full (AF)	1 to Full-1
Almost Empty (AE)	1 to Full-1
Empty (EF)	0

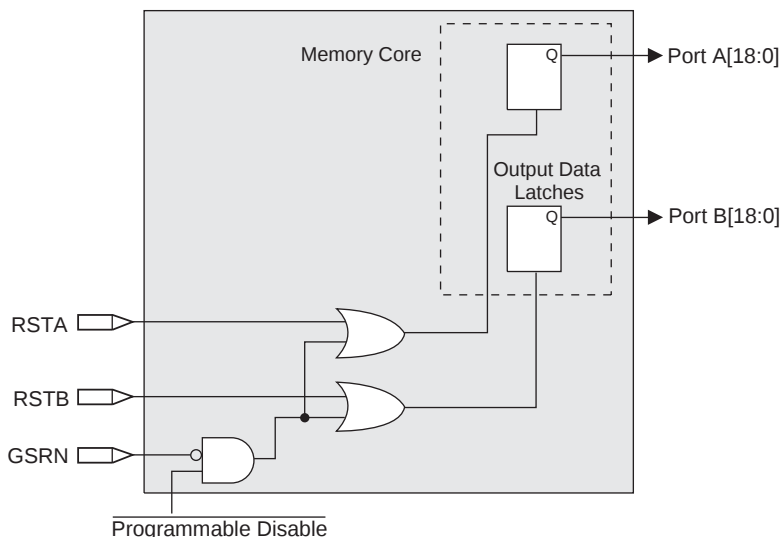
N = Address bit width.

The FIFO state machine supports two types of reset signals: RST and RPRST. The RST signal is a global reset that clears the contents of the FIFO by resetting the read/write pointer and puts the FIFO flags in their initial reset state. The RPRST signal is used to reset the read pointer. The purpose of this reset is to retransmit the data that is in the FIFO. In these applications it is important to keep careful track of when a packet is written into or read from the FIFO.

Memory Core Reset

The memory core contains data output latches for ports A and B. These are simple latches that can be reset synchronously or asynchronously. RSTA and RSTB are local signals, which reset the output latches associated with port A and port B respectively. The Global Reset (GSRN) signal resets both ports. The output data latches and associated resets for both ports are as shown in Figure 2-9.

Figure 2-9. Memory Core Reset

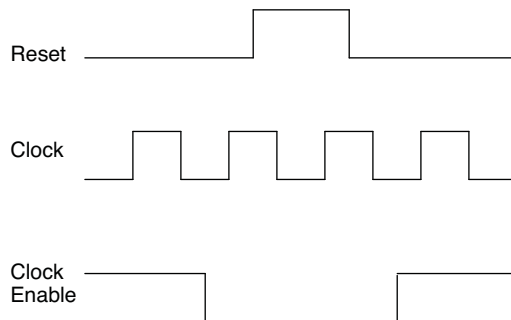


For further information on the sysMEM EBR block, please refer to TN1201, [Memory Usage Guide for MachXO2 Devices](#).

EBR Asynchronous Reset

EBR asynchronous reset or GSR (if used) can only be applied if all clock enables are low for a clock cycle before the reset is applied and released a clock cycle after the reset is released, as shown in Figure 2-10. The GSR input to the EBR is always asynchronous.

Figure 2-10. EBR Asynchronous Reset (Including GSR) Timing Diagram



If all clock enables remain enabled, the EBR asynchronous reset or GSR may only be applied and released after the EBR read and write clock inputs are in a steady state condition for a minimum of $1/f_{MAX}$ (EBR clock). The reset release must adhere to the EBR synchronous reset setup time before the next active read or write clock edge.

If an EBR is pre-loaded during configuration, the GSR input must be disabled or the release of the GSR during device wake up must occur before the release of the device I/Os becoming active.

These instructions apply to all EBR RAM, ROM and FIFO implementations. For the EBR FIFO mode, the GSR signal is always enabled and the WE and RE signals act like the clock enable signals in Figure 2-10. The reset timing rules apply to the RPRreset input versus the RE input and the RST input versus the WE and RE inputs. Both RST and RPRreset are always asynchronous EBR inputs. For more details refer to TN1201, [Memory Usage Guide for MachXO2 Devices](#).

Note that there are no reset restrictions if the EBR synchronous reset is used and the EBR GSR input is disabled.

MachXO2-640U, MachXO2-1200/U, MachXO2-2000/U, MachXO2-4000 and MachXO2-7000 devices contain three types of sysIO buffer pairs.

1. Left and Right sysIO Buffer Pairs

The sysIO buffer pairs in the left and right banks of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the left and right of the devices also have differential and referenced input buffers.

2. Bottom sysIO Buffer Pairs

The sysIO buffer pairs in the bottom bank of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the bottom also have differential and referenced input buffers. Only the I/Os on the bottom banks have programmable PCI clamps and differential input termination. The PCI clamp is enabled after V_{CC} and V_{CCIO} are at valid operating levels and the device has been configured.

3. Top sysIO Buffer Pairs

The sysIO buffer pairs in the top bank of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the top also have differential and referenced I/O buffers. Half of the sysIO buffer pairs on the top edge have true differential outputs. The sysIO buffer pair comprising of the A and B PIOs in every PIC on the top edge have a differential output driver. The referenced input buffer can also be configured as a differential input buffer.

Typical I/O Behavior During Power-up

The internal power-on-reset (POR) signal is deactivated when V_{CC} and V_{CCIO0} have reached V_{PORUP} level defined in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. After the POR signal is deactivated, the FPGA core logic becomes active. It is the user's responsibility to ensure that all V_{CCIO} banks are active with valid input logic levels to properly control the output logic states of all the I/O banks that are critical to the application. The default configuration of the I/O pins in a blank device is tri-state with a weak pull-down to GND (some pins such as PROGRAMN and the JTAG pins have weak pull-up to V_{CCIO} as the default functionality). The I/O pins will maintain the blank configuration until V_{CC} and V_{CCIO} (for I/O banks containing configuration I/Os) have reached V_{PORUP} levels at which time the I/Os will take on the user-configured settings only after a proper download/configuration.

Supported Standards

The MachXO2 sysIO buffer supports both single-ended and differential standards. Single-ended standards can be further subdivided into LVCMOS, LVTTL, and PCI. The buffer supports the LVTTL, PCI, LVCMOS 1.2, 1.5, 1.8, 2.5, and 3.3 V standards. In the LVCMOS and LVTTL modes, the buffer has individually configurable options for drive strength, bus maintenance (weak pull-up, weak pull-down, bus-keeper latch or none) and open drain. BLVDS, MLVDS and LVPECL output emulation is supported on all devices. The MachXO2-640U, MachXO2-1200/U and higher devices support on-chip LVDS output buffers on approximately 50% of the I/Os on the top bank. Differential receivers for LVDS, BLVDS, MLVDS and LVPECL are supported on all banks of MachXO2 devices. PCI support is provided in the bottom bank of the MachXO2-640U, MachXO2-1200/U and higher density devices. Table 2-11 summarizes the I/O characteristics of the MachXO2 PLDs.

Tables 2-11 and 2-12 show the I/O standards (together with their supply and reference voltages) supported by the MachXO2 devices. For further information on utilizing the sysIO buffer to support a variety of standards please see TN1202, [MachXO2 sysIO Usage Guide](#).

Configuration and Testing

This section describes the configuration and testing features of the MachXO2 family.

IEEE 1149.1-Compliant Boundary Scan Testability

All MachXO2 devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant test access port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test access port consists of dedicated I/Os: TDI, TDO, TCK and TMS. The test access port shares its power supply with V_{CCIO} Bank 0 and can operate with LVCMOS3.3, 2.5, 1.8, 1.5, and 1.2 standards.

For more details on boundary scan test, see AN8066, [Boundary Scan Testability with Lattice sysIO Capability](#) and TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#).

Device Configuration

All MachXO2 devices contain two ports that can be used for device configuration. The Test Access Port (TAP), which supports bit-wide configuration and the sysCONFIG port which supports serial configuration through I²C or SPI. The TAP supports both the IEEE Standard 1149.1 Boundary Scan specification and the IEEE Standard 1532 In-System Configuration specification. There are various ways to configure a MachXO2 device:

1. Internal Flash Download
2. JTAG
3. Standard Serial Peripheral Interface (Master SPI mode) – interface to boot PROM memory
4. System microprocessor to drive a serial slave SPI port (SSPI mode)
5. Standard I²C Interface to system microprocessor

Upon power-up, the configuration SRAM is ready to be configured using the selected sysCONFIG port. Once a configuration port is selected, it will remain active throughout that configuration cycle. The IEEE 1149.1 port can be activated any time after power-up by sending the appropriate command through the TAP port. Optionally the device can run a CRC check upon entering the user mode. This will ensure that the device was configured correctly.

The sysCONFIG port has 10 dual-function pins which can be used as general purpose I/Os if they are not required for configuration. See TN1204, [MachXO2 Programming and Configuration Usage Guide](#) for more information about using the dual-use pins as general purpose I/Os.

Lattice design software uses proprietary compression technology to compress bit-streams for use in MachXO2 devices. Use of this technology allows Lattice to provide a lower cost solution. In the unlikely event that this technology is unable to compress bitstreams to fit into the amount of on-chip Flash memory, there are a variety of techniques that can be utilized to allow the bitstream to fit in the on-chip Flash memory. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

The Test Access Port (TAP) has five dual purpose pins (TDI, TDO, TMS, TCK and JTAGENB). These pins are dual function pins - TDI, TDO, TMS and TCK can be used as general purpose I/O if desired. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

TransFR (Transparent Field Reconfiguration)

TransFR is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a simple push-button solution. For more details refer to TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) for details.

sysIO Single-Ended DC Electrical Characteristics^{1, 2}

Input/Output Standard	V_{IL}		V_{IH}		V_{OL} Max. (V)	V_{OH} Min. (V)	I_{OL} Max. ⁴ (mA)	I_{OH} Max. ⁴ (mA)
	Min. (V) ³	Max. (V)	Min. (V)	Max. (V)				
LVCMOS 3.3 LVTTL	-0.3	0.8	2.0	3.6	0.4	$V_{CCIO} - 0.4$	4	-4
							8	-8
							12	-12
							16	-16
							24	-24
					0.2	$V_{CCIO} - 0.2$	0.1	-0.1
LVCMOS 2.5	-0.3	0.7	1.7	3.6	0.4	$V_{CCIO} - 0.4$	4	-4
							8	-8
							12	-12
							16	-16
					0.2	$V_{CCIO} - 0.2$	0.1	-0.1
LVCMOS 1.8	-0.3	$0.35V_{CCIO}$	$0.65V_{CCIO}$	3.6	0.4	$V_{CCIO} - 0.4$	4	-4
							8	-8
							12	-12
					0.2	$V_{CCIO} - 0.2$	0.1	-0.1
LVCMOS 1.5	-0.3	$0.35V_{CCIO}$	$0.65V_{CCIO}$	3.6	0.4	$V_{CCIO} - 0.4$	4	-4
					0.2	$V_{CCIO} - 0.2$	0.1	-0.1
LVCMOS 1.2	-0.3	$0.35V_{CCIO}$	$0.65V_{CCIO}$	3.6	0.4	$V_{CCIO} - 0.4$	4	-2
							8	-6
					0.2	$V_{CCIO} - 0.2$	0.1	-0.1
PCI	-0.3	$0.3V_{CCIO}$	$0.5V_{CCIO}$	3.6	$0.1V_{CCIO}$	$0.9V_{CCIO}$	1.5	-0.5
SSTL25 Class I	-0.3	$V_{REF} - 0.18$	$V_{REF} + 0.18$	3.6	0.54	$V_{CCIO} - 0.62$	8	8
SSTL25 Class II	-0.3	$V_{REF} - 0.18$	$V_{REF} + 0.18$	3.6	NA	NA	NA	NA
SSTL18 Class I	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	3.6	0.40	$V_{CCIO} - 0.40$	8	8
SSTL18 Class II	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	3.6	NA	NA	NA	NA
HSTL18 Class I	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	$V_{CCIO} - 0.40$	8	8
HSTL18 Class II	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS25R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS18R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS18R25	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS15R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS15R25	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS12R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	NA Open Drain	24, 16, 12, 8, 4	NA Open Drain
LVCMOS12R25	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	NA Open Drain	16, 12, 8, 4	NA Open Drain
LVCMOS10R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	NA Open Drain	24, 16, 12, 8, 4	NA Open Drain

Typical Building Block Function Performance – HC/HE Devices¹

Pin-to-Pin Performance (LVCMOS25 12 mA Drive)

Function	-6 Timing	Units
Basic Functions		
16-bit decoder	8.9	ns
4:1 MUX	7.5	ns
16:1 MUX	8.3	ns

Register-to-Register Performance

Function	-6 Timing	Units
Basic Functions		
16:1 MUX	412	MHz
16-bit adder	297	MHz
16-bit counter	324	MHz
64-bit counter	161	MHz
Embedded Memory Functions		
1024x9 True-Dual Port RAM (Write Through or Normal, EBR output registers)	183	MHz
Distributed Memory Functions		
16x4 Pseudo-Dual Port RAM (one PFU)	500	MHz

1. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.

Typical Building Block Function Performance – ZE Devices¹

Pin-to-Pin Performance (LVCMOS25 12 mA Drive)

Function	–3 Timing	Units
Basic Functions		
16-bit decoder	13.9	ns
4:1 MUX	10.9	ns
16:1 MUX	12.0	ns

Register-to-Register Performance

Function	–3 Timing	Units
Basic Functions		
16:1 MUX	191	MHz
16-bit adder	134	MHz
16-bit counter	148	MHz
64-bit counter	77	MHz
Embedded Memory Functions		
1024x9 True-Dual Port RAM (Write Through or Normal, EBR output registers)	90	MHz
Distributed Memory Functions		
16x4 Pseudo-Dual Port RAM (one PFU)	214	MHz

1. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.

Derating Logic Timing

Logic timing provided in the following sections of the data sheet and the Lattice design tools are worst case numbers in the operating range. Actual delays may be much faster. Lattice design tools can provide logic timing numbers at a particular temperature and voltage.

Maximum sysIO Buffer Performance

I/O Standard	Max. Speed	Units
LVDS25	400	MHz
LVDS25E	150	MHz
RSDS25	150	MHz
RSDS25E	150	MHz
BLVDS25	150	MHz
BLVDS25E	150	MHz
MLVDS25	150	MHz
MLVDS25E	150	MHz
LVPECL33	150	MHz
LVPECL33E	150	MHz
SSTL25_I	150	MHz
SSTL25_II	150	MHz
SSTL25D_I	150	MHz
SSTL25D_II	150	MHz
SSTL18_I	150	MHz
SSTL18_II	150	MHz
SSTL18D_I	150	MHz
SSTL18D_II	150	MHz
HSTL18_I	150	MHz
HSTL18_II	150	MHz
HSTL18D_I	150	MHz
HSTL18D_II	150	MHz
PCI33	134	MHz
LVTTTL33	150	MHz
LVTTTL33D	150	MHz
LVC MOS33	150	MHz
LVC MOS33D	150	MHz
LVC MOS25	150	MHz
LVC MOS25D	150	MHz
LVC MOS25R33	150	MHz
LVC MOS18	150	MHz
LVC MOS18D	150	MHz
LVC MOS18R33	150	MHz
LVC MOS18R25	150	MHz
LVC MOS15	150	MHz
LVC MOS15D	150	MHz
LVC MOS15R33	150	MHz
LVC MOS15R25	150	MHz
LVC MOS12	91	MHz
LVC MOS12D	91	MHz

Parameter	Description	Device	-6		-5		-4		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
Generic DDRX2 Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDRX2_TX.ECLK.Centered ^{9, 12}									
t _{DVB}	Output Data Valid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	0.535	—	0.670	—	0.830	—	ns
t _{DVA}	Output Data Valid After CLK Output		0.535	—	0.670	—	0.830	—	ns
f _{DATA}	DDRX2 Serial Output Data Speed		—	664	—	554	—	462	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency (minimum limited by PLL)		—	332	—	277	—	231	MHz
f _{SCLK}	SCLK Frequency		—	166	—	139	—	116	MHz
Generic DDRX4 Outputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDRX4_TX.ECLK.Aligned ^{9, 12}									
t _{DIA}	Output Data Invalid After CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	—	0.200	—	0.215	—	0.230	ns
t _{DIB}	Output Data Invalid Before CLK Output		—	0.200	—	0.215	—	0.230	ns
f _{DATA}	DDRX4 Serial Output Data Speed		—	756	—	630	—	524	Mbps
f _{DDRX4}	DDRX4 ECLK Frequency		—	378	—	315	—	262	MHz
f _{SCLK}	SCLK Frequency		—	95	—	79	—	66	MHz
Generic DDRX4 Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDRX4_TX.ECLK.Centered ^{9, 12}									
t _{DVB}	Output Data Valid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	0.455	—	0.570	—	0.710	—	ns
t _{DVA}	Output Data Valid After CLK Output		0.455	—	0.570	—	0.710	—	ns
f _{DATA}	DDRX4 Serial Output Data Speed		—	756	—	630	—	524	Mbps
f _{DDRX4}	DDRX4 ECLK Frequency (minimum limited by PLL)		—	378	—	315	—	262	MHz
f _{SCLK}	SCLK Frequency		—	95	—	79	—	66	MHz
7:1 LVDS Outputs – GDDR71_TX.ECLK.7:1 ^{9, 12}									
t _{DIB}	Output Data Invalid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	—	0.160	—	0.180	—	0.200	ns
t _{DIA}	Output Data Invalid After CLK Output		—	0.160	—	0.180	—	0.200	ns
f _{DATA}	DDR71 Serial Output Data Speed		—	756	—	630	—	524	Mbps
f _{DDR71}	DDR71 ECLK Frequency		—	378	—	315	—	262	MHz
f _{CLKOUT}	7:1 Output Clock Frequency (SCLK) (minimum limited by PLL)		—	108	—	90	—	75	MHz

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t _{SU_DEL}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-256ZE	2.62	—	2.91	—	3.14	—	ns
		MachXO2-640ZE	2.56	—	2.85	—	3.08	—	ns
		MachXO2-1200ZE	2.30	—	2.57	—	2.79	—	ns
		MachXO2-2000ZE	2.25	—	2.50	—	2.70	—	ns
		MachXO2-4000ZE	2.39	—	2.60	—	2.76	—	ns
		MachXO2-7000ZE	2.17	—	2.33	—	2.43	—	ns
t _{H_DEL}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-256ZE	–0.44	—	–0.44	—	–0.44	—	ns
		MachXO2-640ZE	–0.43	—	–0.43	—	–0.43	—	ns
		MachXO2-1200ZE	–0.28	—	–0.28	—	–0.28	—	ns
		MachXO2-2000ZE	–0.31	—	–0.31	—	–0.31	—	ns
		MachXO2-4000ZE	–0.34	—	–0.34	—	–0.34	—	ns
		MachXO2-7000ZE	–0.21	—	–0.21	—	–0.21	—	ns
f _{MAX_IO}	Clock Frequency of I/O and PFU Register	All MachXO2 devices	—	150	—	125	—	104	MHz
General I/O Pin Parameters (Using Edge Clock without PLL)									
t _{COE}	Clock to Output – PIO Output Register	MachXO2-1200ZE	—	11.10	—	11.51	—	11.91	ns
		MachXO2-2000ZE	—	11.10	—	11.51	—	11.91	ns
		MachXO2-4000ZE	—	10.89	—	11.28	—	11.67	ns
		MachXO2-7000ZE	—	11.10	—	11.51	—	11.91	ns
t _{SUE}	Clock to Data Setup – PIO Input Register	MachXO2-1200ZE	–0.23	—	–0.23	—	–0.23	—	ns
		MachXO2-2000ZE	–0.23	—	–0.23	—	–0.23	—	ns
		MachXO2-4000ZE	–0.15	—	–0.15	—	–0.15	—	ns
		MachXO2-7000ZE	–0.23	—	–0.23	—	–0.23	—	ns
t _{HE}	Clock to Data Hold – PIO Input Register	MachXO2-1200ZE	3.81	—	4.11	—	4.52	—	ns
		MachXO2-2000ZE	3.81	—	4.11	—	4.52	—	ns
		MachXO2-4000ZE	3.60	—	3.89	—	4.28	—	ns
		MachXO2-7000ZE	3.81	—	4.11	—	4.52	—	ns
t _{SU_DELE}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-1200ZE	2.78	—	3.11	—	3.40	—	ns
		MachXO2-2000ZE	2.78	—	3.11	—	3.40	—	ns
		MachXO2-4000ZE	3.11	—	3.48	—	3.79	—	ns
		MachXO2-7000ZE	2.94	—	3.30	—	3.60	—	ns
t _{H_DELE}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-1200ZE	–0.29	—	–0.29	—	–0.29	—	ns
		MachXO2-2000ZE	–0.29	—	–0.29	—	–0.29	—	ns
		MachXO2-4000ZE	–0.46	—	–0.46	—	–0.46	—	ns
		MachXO2-7000ZE	–0.37	—	–0.37	—	–0.37	—	ns
General I/O Pin Parameters (Using Primary Clock with PLL)									
t _{COPLL}	Clock to Output – PIO Output Register	MachXO2-1200ZE	—	7.95	—	8.07	—	8.19	ns
		MachXO2-2000ZE	—	7.97	—	8.10	—	8.22	ns
		MachXO2-4000ZE	—	7.98	—	8.10	—	8.23	ns
		MachXO2-7000ZE	—	8.02	—	8.14	—	8.26	ns
t _{SUPLL}	Clock to Data Setup – PIO Input Register	MachXO2-1200ZE	0.85	—	0.85	—	0.89	—	ns
		MachXO2-2000ZE	0.84	—	0.84	—	0.86	—	ns
		MachXO2-4000ZE	0.84	—	0.84	—	0.85	—	ns
		MachXO2-7000ZE	0.83	—	0.83	—	0.81	—	ns

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
Generic DDR4 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR4_RX.ECLK.Centered ^{9, 12}									
t _{SU}	Input Data Setup Before ECLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	0.434	—	0.535	—	0.630	—	ns
t _{HO}	Input Data Hold After ECLK		0.385	—	0.395	—	0.463	—	ns
f _{DATA}	DDR4 Serial Input Data Speed		—	420	—	352	—	292	Mbps
f _{DDR4}	DDR4 ECLK Frequency		—	210	—	176	—	146	MHz
f _{SCLK}	SCLK Frequency		—	53	—	44	—	37	MHz
7:1 LVDS Inputs – GDDR71_RX.ECLK.7.1 ^{9, 12}									
t _{DVA}	Input Data Valid After ECLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	—	0.307	—	0.316	—	0.326	UI
t _{DVE}	Input Data Hold After ECLK		0.662	—	0.650	—	0.649	—	UI
f _{DATA}	DDR71 Serial Input Data Speed		—	420	—	352	—	292	Mbps
f _{DDR71}	DDR71 ECLK Frequency		—	210	—	176	—	146	MHz
f _{CLKIN}	7:1 Input Clock Frequency (SCLK) (minimum limited by PLL)		—	60	—	50	—	42	MHz
Generic DDR Outputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR1_TX.SCLK.Aligned ^{9, 12}									
t _{DIA}	Output Data Invalid After CLK Output	All MachXO2 devices, all sides	—	0.850	—	0.910	—	0.970	ns
t _{DIB}	Output Data Invalid Before CLK Output		—	0.850	—	0.910	—	0.970	ns
f _{DATA}	DDR1 Output Data Speed		—	140	—	116	—	98	Mbps
f _{DDR1}	DDR1 SCLK frequency		—	70	—	58	—	49	MHz
Generic DDR Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR1_TX.SCLK.Centered ^{9, 12}									
t _{DVB}	Output Data Valid Before CLK Output	All MachXO2 devices, all sides	2.720	—	3.380	—	4.140	—	ns
t _{DVA}	Output Data Valid After CLK Output		2.720	—	3.380	—	4.140	—	ns
f _{DATA}	DDR1 Output Data Speed		—	140	—	116	—	98	Mbps
f _{DDR1}	DDR1 SCLK Frequency (minimum limited by PLL)		—	70	—	58	—	49	MHz
Generic DDRX2 Outputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR2_TX.ECLK.Aligned ^{9, 12}									
t _{DIA}	Output Data Invalid After CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only	—	0.270	—	0.300	—	0.330	ns
t _{DIB}	Output Data Invalid Before CLK Output		—	0.270	—	0.300	—	0.330	ns
f _{DATA}	DDR2 Serial Output Data Speed		—	280	—	234	—	194	Mbps
f _{DDR2}	DDR2 ECLK frequency		—	140	—	117	—	97	MHz
f _{SCLK}	SCLK Frequency		—	70	—	59	—	49	MHz

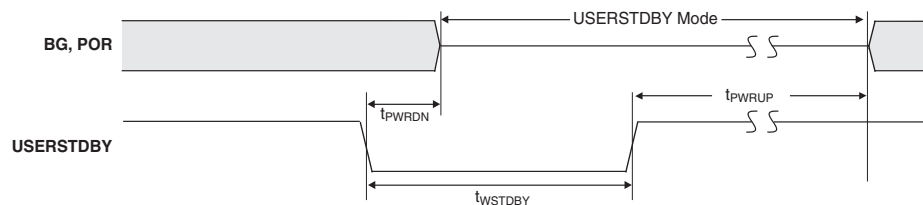
MachXO2 Oscillator Output Frequency

Symbol	Parameter	Min.	Typ.	Max	Units
f_{MAX}	Oscillator Output Frequency (Commercial Grade Devices, 0 to 85°C)	125.685	133	140.315	MHz
	Oscillator Output Frequency (Industrial Grade Devices, -40 °C to 100 °C)	124.355	133	141.645	MHz
t_{DT}	Output Clock Duty Cycle	43	50	57	%
t_{OPJIT}^1	Output Clock Period Jitter	0.01	0.012	0.02	UIPP
$t_{STABLEOSC}$	STDBY Low to Oscillator Stable	0.01	0.05	0.1	μs

1. Output Clock Period Jitter specified at 133 MHz. The values for lower frequencies will be smaller UIPP. The typical value for 133 MHz is 95 ps and for 2.08 MHz the typical value is 1.54 ns.

MachXO2 Standby Mode Timing – HC/HE Devices

Symbol	Parameter	Device	Min.	Typ.	Max	Units
t_{PWRDN}	USERSTDBY High to Stop	All	—	—	9	ns
t_{PWRUP}	USERSTDBY Low to Power Up	LCMXO2-256		—		μs
		LCMXO2-640		—		μs
		LCMXO2-640U		—		μs
		LCMXO2-1200	20	—	50	μs
		LCMXO2-1200U		—		μs
		LCMXO2-2000		—		μs
		LCMXO2-2000U		—		μs
		LCMXO2-4000		—		μs
		LCMXO2-7000		—		μs
t_{WSTDBY}	USERSTDBY Pulse Width	All	18	—	—	ns



MachXO2 Standby Mode Timing – ZE Devices

Symbol	Parameter	Device	Min.	Typ.	Max	Units
t_{PWRDN}	USERSTDBY High to Stop	All	—	—	13	ns
t_{PWRUP}	USERSTDBY Low to Power Up	LCMXO2-256		—		μs
		LCMXO2-640		—		μs
		LCMXO2-1200	20	—	50	μs
		LCMXO2-2000		—		μs
		LCMXO2-4000		—		μs
		LCMXO2-7000		—		μs
t_{WSTDBY}	USERSTDBY Pulse Width	All	19	—	—	ns
$t_{BNDGAPSTBL}$	USERSTDBY High to Bandgap Stable	All	—	—	15	ns

I²C Port Timing Specifications^{1, 2}

Symbol	Parameter	Min.	Max.	Units
f _{MAX}	Maximum SCL clock frequency	—	400	kHz

- MachXO2 supports the following modes:
 - Standard-mode (Sm), with a bit rate up to 100 kbit/s (user and configuration mode)
 - Fast-mode (Fm), with a bit rate up to 400 kbit/s (user and configuration mode)
- Refer to the I²C specification for timing requirements.

SPI Port Timing Specifications¹

Symbol	Parameter	Min.	Max.	Units
f _{MAX}	Maximum SCK clock frequency	—	45	MHz

- Applies to user mode only. For configuration mode timing specifications, refer to sysCONFIG Port Timing Specifications table in this data sheet.

Switching Test Conditions

Figure 3-13 shows the output test load used for AC testing. The specific values for resistance, capacitance, voltage, and other test conditions are shown in Table 3-5.

Figure 3-13. Output Test Load, LVTTTL and LVCMOS Standards

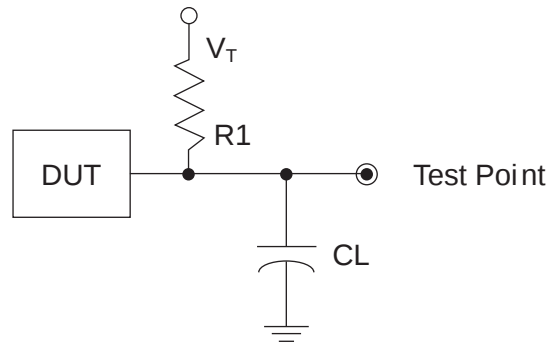


Table 3-5. Test Fixture Required Components, Non-Terminated Interfaces

Test Condition	R1	CL	Timing Ref.	VT
LVTTTL and LVCMOS settings (L -> H, H -> L)	∞	0pF	LVTTTL, LVCMOS 3.3 = 1.5 V	—
			LVCMOS 2.5 = V _{CCIO} /2	—
			LVCMOS 1.8 = V _{CCIO} /2	—
			LVCMOS 1.5 = V _{CCIO} /2	—
			LVCMOS 1.2 = V _{CCIO} /2	—
LVTTTL and LVCMOS 3.3 (Z -> H)	188	0pF	1.5 V	V _{OL}
LVTTTL and LVCMOS 3.3 (Z -> L)			1.5 V	V _{OH}
Other LVCMOS (Z -> H)			V _{CCIO} /2	V _{OL}
Other LVCMOS (Z -> L)			V _{CCIO} /2	V _{OH}
LVTTTL + LVCMOS (H -> Z)			V _{OH} - 0.15 V	V _{OL}
LVTTTL + LVCMOS (L -> Z)			V _{OL} - 0.15 V	V _{OH}

Note: Output test conditions for all other interfaces are determined by the respective standards.

	MachXO2-1200					MachXO2-1200U
	100 TQFP	132 csBGA	144 TQFP	25 WLCSP	32 QFN ¹	256 ftBGA
General Purpose I/O per Bank						
Bank 0	18	25	27	11	9	50
Bank 1	21	26	26	0	2	52
Bank 2	20	28	28	7	9	52
Bank 3	20	25	26	0	2	16
Bank 4	0	0	0	0	0	16
Bank 5	0	0	0	0	0	20
Total General Purpose Single Ended I/O	79	104	107	18	22	206
Differential I/O per Bank						
Bank 0	9	13	14	5	4	25
Bank 1	10	13	13	0	1	26
Bank 2	10	14	14	2	4	26
Bank 3	10	12	13	0	1	8
Bank 4	0	0	0	0	0	8
Bank 5	0	0	0	0	0	10
Total General Purpose Differential I/O	39	52	54	7	10	103
Dual Function I/O						
	31	33	33	18	22	33
High-speed Differential I/O						
Bank 0	4	7	7	0	0	14
Gearboxes						
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	4	7	7	0	0	14
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	5	7	7	0	2	14
DQS Groups						
Bank 1	1	2	2	0	0	2
VCCIO Pins						
Bank 0	2	3	3	1	2	4
Bank 1	2	3	3	0	1	4
Bank 2	2	3	3	1	2	4
Bank 3	3	3	3	0	1	1
Bank 4	0	0	0	0	0	2
Bank 5	0	0	0	0	0	1
VCC						
	2	4	4	2	2	8
GND						
	8	10	12	2	2	24
NC						
	1	1	8	0	0	1
Reserved for Configuration						
	1	1	1	1	1	1
Total Count of Bonded Pins	100	132	144	25	32	256

1. Lattice recommends soldering the central thermal pad onto the top PCB ground for improved thermal resistance.

	MachXO2-2000						MachXO2-2000U
	49 WLCSP	100 TQFP	132 csBGA	144 TQFP	256 caBGA	256 ftBGA	484 ftBGA
General Purpose I/O per Bank							
Bank 0	19	18	25	27	50	50	70
Bank 1	0	21	26	28	52	52	68
Bank 2	13	20	28	28	52	52	72
Bank 3	0	6	7	8	16	16	24
Bank 4	0	6	8	10	16	16	16
Bank 5	6	8	10	10	20	20	28
Total General Purpose Single-Ended I/O	38	79	104	111	206	206	278
Differential I/O per Bank							
Bank 0	7	9	13	14	25	25	35
Bank 1	0	10	13	14	26	26	34
Bank 2	6	10	14	14	26	26	36
Bank 3	0	3	3	4	8	8	12
Bank 4	0	3	4	5	8	8	8
Bank 5	3	4	5	5	10	10	14
Total General Purpose Differential I/O	16	39	52	56	103	103	139
Dual Function I/O							
	24	31	33	33	33	33	37
High-speed Differential I/O							
Bank 0	5	4	8	9	14	14	18
Gearboxes							
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	5	4	8	9	14	14	18
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	6	10	14	14	14	14	18
DQS Groups							
Bank 1	0	1	2	2	2	2	2
VCCIO Pins							
Bank 0	2	2	3	3	4	4	10
Bank 1	0	2	3	3	4	4	10
Bank 2	1	2	3	3	4	4	10
Bank 3	0	1	1	1	1	1	3
Bank 4	0	1	1	1	2	2	4
Bank 5	1	1	1	1	1	1	3
VCC	2	2	4	4	8	8	12
GND	4	8	10	12	24	24	48
NC	0	1	1	4	1	1	105
Reserved for Configuration	1	1	1	1	v	1	1
Total Count of Bonded Pins	39	100	132	144	256	256	484

	MachXO2-4000							
	84 QFN	132 csBGA	144 TQFP	184 csBGA	256 caBGA	256 ftBGA	332 caBGA	484 fpBGA
General Purpose I/O per Bank								
Bank 0	27	25	27	37	50	50	68	70
Bank 1	10	26	29	37	52	52	68	68
Bank 2	22	28	29	39	52	52	70	72
Bank 3	0	7	9	10	16	16	24	24
Bank 4	9	8	10	12	16	16	16	16
Bank 5	0	10	10	15	20	20	28	28
Total General Purpose Single Ended I/O	68	104	114	150	206	206	274	278
Differential I/O per Bank								
Bank 0	13	13	14	18	25	25	34	35
Bank 1	4	13	14	18	26	26	34	34
Bank 2	11	14	14	19	26	26	35	36
Bank 3	0	3	4	4	8	8	12	12
Bank 4	4	4	5	6	8	8	8	8
Bank 5	0	5	5	7	10	10	14	14
Total General Purpose Differential I/O	32	52	56	72	103	103	137	139
Dual Function I/O								
	28	37	37	37	37	37	37	37
High-speed Differential I/O								
Bank 0	8	8	9	8	18	18	18	18
Gearboxes								
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	8	8	9	9	18	18	18	18
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	11	14	14	12	18	18	18	18
DQS Groups								
Bank 1	1	2	2	2	2	2	2	2
VCCIO Pins								
Bank 0	3	3	3	3	4	4	4	10
Bank 1	1	3	3	3	4	4	4	10
Bank 2	2	3	3	3	4	4	4	10
Bank 3	1	1	1	1	1	1	2	3
Bank 4	1	1	1	1	2	2	1	4
Bank 5	1	1	1	1	1	1	2	3
VCC								
	4	4	4	4	8	8	8	12
GND								
	4	10	12	16	24	24	27	48
NC								
	1	1	1	1	1	1	5	105
Reserved for configuration								
	1	1	1	1	1	1	1	1
Total Count of Bonded Pins	84	132	144	184	256	256	332	484

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200HC-4SG32C	1280	2.5 V / 3.3 V	–4	Halogen-Free QFN	32	COM
LCMXO2-1200HC-5SG32C	1280	2.5 V / 3.3 V	–5	Halogen-Free QFN	32	COM
LCMXO2-1200HC-6SG32C	1280	2.5 V / 3.3 V	–6	Halogen-Free QFN	32	COM
LCMXO2-1200HC-4TG100C	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-5TG100C	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-6TG100C	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-4MG132C	1280	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-5MG132C	1280	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-6MG132C	1280	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-4TG144C	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	COM
LCMXO2-1200HC-5TG144C	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	COM
LCMXO2-1200HC-6TG144C	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200UHC-4FTG256C	1280	2.5 V / 3.3 V	–4	Halogen-Free ftBGA	256	COM
LCMXO2-1200UHC-5FTG256C	1280	2.5 V / 3.3 V	–5	Halogen-Free ftBGA	256	COM
LCMXO2-1200UHC-6FTG256C	1280	2.5 V / 3.3 V	–6	Halogen-Free ftBGA	256	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000HC-4TG100C	2112	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	COM
LCMXO2-2000HC-5TG100C	2112	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	COM
LCMXO2-2000HC-6TG100C	2112	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	COM
LCMXO2-2000HC-4MG132C	2112	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	COM
LCMXO2-2000HC-5MG132C	2112	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	COM
LCMXO2-2000HC-6MG132C	2112	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	COM
LCMXO2-2000HC-4TG144C	2112	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	COM
LCMXO2-2000HC-5TG144C	2112	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	COM
LCMXO2-2000HC-6TG144C	2112	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	COM
LCMXO2-2000HC-4BG256C	2112	2.5 V / 3.3 V	–4	Halogen-Free caBGA	256	COM
LCMXO2-2000HC-5BG256C	2112	2.5 V / 3.3 V	–5	Halogen-Free caBGA	256	COM
LCMXO2-2000HC-6BG256C	2112	2.5 V / 3.3 V	–6	Halogen-Free caBGA	256	COM
LCMXO2-2000HC-4FTG256C	2112	2.5 V / 3.3 V	–4	Halogen-Free ftBGA	256	COM
LCMXO2-2000HC-5FTG256C	2112	2.5 V / 3.3 V	–5	Halogen-Free ftBGA	256	COM
LCMXO2-2000HC-6FTG256C	2112	2.5 V / 3.3 V	–6	Halogen-Free ftBGA	256	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200HC-4TG100IR1 ¹	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-5TG100IR1 ¹	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-6TG100IR1 ¹	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-4MG132IR1 ¹	1280	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-5MG132IR1 ¹	1280	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-6MG132IR1 ¹	1280	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-4TG144IR1 ¹	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-5TG144IR1 ¹	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-6TG144IR1 ¹	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	IND

1. Specifications for the “LCMXO2-1200HC-speed package IR1” are the same as the “LCMXO2-1200ZE-speed package I” devices respectively, except as specified in the [R1 Device Specifications](#) section of this data sheet.

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-4000HE-4MG132I	4320	1.2 V	–4	Halogen-Free csBGA	132	IND
LCMXO2-4000HE-5MG132I	4320	1.2 V	–5	Halogen-Free csBGA	132	IND
LCMXO2-4000HE-6MG132I	4320	1.2 V	–6	Halogen-Free csBGA	132	IND
LCMXO2-4000HE-4TG144I	4320	1.2 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-4000HE-5TG144I	4320	1.2 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-4000HE-6TG144I	4320	1.2 V	–6	Halogen-Free TQFP	144	IND
LCMXO2-4000HE-4MG184I	4320	1.2 V	–4	Halogen-Free csBGA	184	IND
LCMXO2-4000HE-5MG184I	4320	1.2 V	–5	Halogen-Free csBGA	184	IND
LCMXO2-4000HE-6MG184I	4320	1.2 V	–6	Halogen-Free csBGA	184	IND
LCMXO2-4000HE-4BG256I	4320	1.2 V	–4	Halogen-Free caBGA	256	IND
LCMXO2-4000HE-5BG256I	4320	1.2 V	–5	Halogen-Free caBGA	256	IND
LCMXO2-4000HE-6BG256I	4320	1.2 V	–6	Halogen-Free caBGA	256	IND
LCMXO2-4000HE-4FTG256I	4320	1.2 V	–4	Halogen-Free ftBGA	256	IND
LCMXO2-4000HE-5FTG256I	4320	1.2 V	–5	Halogen-Free ftBGA	256	IND
LCMXO2-4000HE-6FTG256I	4320	1.2 V	–6	Halogen-Free ftBGA	256	IND
LCMXO2-4000HE-4BG332I	4320	1.2 V	–4	Halogen-Free caBGA	332	IND
LCMXO2-4000HE-5BG332I	4320	1.2 V	–5	Halogen-Free caBGA	332	IND
LCMXO2-4000HE-6BG332I	4320	1.2 V	–6	Halogen-Free caBGA	332	IND
LCMXO2-4000HE-4FG484I	4320	1.2 V	–4	Halogen-Free fpBGA	484	IND
LCMXO2-4000HE-5FG484I	4320	1.2 V	–5	Halogen-Free fpBGA	484	IND
LCMXO2-4000HE-6FG484I	4320	1.2 V	–6	Halogen-Free fpBGA	484	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-7000HE-4TG144I	6864	1.2 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-7000HE-5TG144I	6864	1.2 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-7000HE-6TG144I	6864	1.2 V	–6	Halogen-Free TQFP	144	IND
LCMXO2-7000HE-4BG256I	6864	1.2 V	–4	Halogen-Free caBGA	256	IND
LCMXO2-7000HE-5BG256I	6864	1.2 V	–5	Halogen-Free caBGA	256	IND
LCMXO2-7000HE-6BG256I	6864	1.2 V	–6	Halogen-Free caBGA	256	IND
LCMXO2-7000HE-4FTG256I	6864	1.2 V	–4	Halogen-Free ftBGA	256	IND
LCMXO2-7000HE-5FTG256I	6864	1.2 V	–5	Halogen-Free ftBGA	256	IND
LCMXO2-7000HE-6FTG256I	6864	1.2 V	–6	Halogen-Free ftBGA	256	IND
LCMXO2-7000HE-4BG332I	6864	1.2 V	–4	Halogen-Free caBGA	332	IND
LCMXO2-7000HE-5BG332I	6864	1.2 V	–5	Halogen-Free caBGA	332	IND
LCMXO2-7000HE-6BG332I	6864	1.2 V	–6	Halogen-Free caBGA	332	IND
LCMXO2-7000HE-4FG484I	6864	1.2 V	–4	Halogen-Free fpBGA	484	IND
LCMXO2-7000HE-5FG484I	6864	1.2 V	–5	Halogen-Free fpBGA	484	IND
LCMXO2-7000HE-6FG484I	6864	1.2 V	–6	Halogen-Free fpBGA	484	IND

For Further Information

A variety of technical notes for the MachXO2 family are available on the Lattice web site.

- TN1198, [Power Estimation and Management for MachXO2 Devices](#)
- TN1199, [MachXO2 sysCLOCK PLL Design and Usage Guide](#)
- TN1201, [Memory Usage Guide for MachXO2 Devices](#)
- TN1202, [MachXO2 sysIO Usage Guide](#)
- TN1203, [Implementing High-Speed Interfaces with MachXO2 Devices](#)
- TN1204, [MachXO2 Programming and Configuration Usage Guide](#)
- TN1205, [Using User Flash Memory and Hardened Control Functions in MachXO2 Devices](#)
- TN1206, [MachXO2 SRAM CRC Error Detection Usage Guide](#)
- TN1207, [Using TraceID in MachXO2 Devices](#)
- TN1074, [PCB Layout Recommendations for BGA Packages](#)
- TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#)
- AN8086, [Designing for Migration from MachXO2-1200-R1 to Standard \(non-R1\) Devices](#)
- AN8066, [Boundary Scan Testability with Lattice sysIO Capability](#)
- [MachXO2 Device Pinout Files](#)
- [Thermal Management](#) document
- [Lattice design tools](#)

For further information on interface standards, refer to the following web sites:

- JEDEC Standards (LVTTTL, LVCMOS, LVDS, DDR, DDR2, LPDDR): www.jedec.org
- PCI: www.pcisig.com